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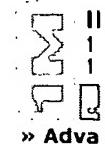


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- What Can I Access?
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- Conference Proceedings
- Standards

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- By Author
- Basic
- Advanced
- CrossRef

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(signal <phrase> (detection  
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<phrase> (indicator <or>  
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- Home
- What Can I Access?
- Log-out

**Tables of Contents**

- Journals & Magazines
- Conference Proceedings
- Standards

**Search**

- By Author
- Basic
- Advanced
- CrossRef

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- Access the IEEE Member Digital Library

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 [Print Format](#)[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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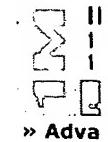


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Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

#### Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

#### Search

- By Author
- Basic
- Advanced
- CrossRef

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- Join IEEE
- Establish IEEE Web Account
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```
(internal <phrase> computer
<phrase> (state <or> status
<or> condition))
```

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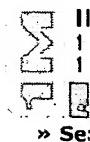


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Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

#### Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

#### Search

- By Author
- Basic
- Advanced
- CrossRef

#### Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

#### IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

[Print Format](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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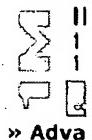


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Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

#### Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

#### Search

- By Author
- Basic
- Advanced
- CrossRef

#### Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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- IEEE Conference proceedings
- IEE Conference proceedings
- IEEE Standards

##### Select years to search:

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##### Organize search results by:

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List   Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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#### Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

#### Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

#### Search

- By Author
- Basic
- Advanced
- CrossRef

#### Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

#### IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

[Print Format](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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- [Home](#)
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- [Log-out](#)

#### Tables of Contents

- [Journals & Magazines](#)
- [Conference Proceedings](#)
- [Standards](#)

#### Search

- [By Author](#)
- [Basic](#)
- [Advanced](#)
- [CrossRef](#)

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- [Establish IEEE Web Account](#)
- [Access the IEEE Member Digital Library](#)

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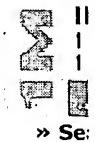
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In:   order

List   Results per page

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» Se:

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- Home
- What Can I Access?
- Log-out

**Tables of Contents**

- Journals & Magazines
- Conference Proceedings
- Standards

**Search**

- By Author
- Basic
- Advanced
- CrossRef

**Member Services**

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

**IEEE Enterprise**

- Access the IEEE Enterprise File Cabinet

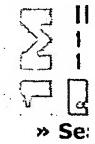
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- [Home](#)
- [What Can I Access?](#)
- [Log-out](#)

**Tables of Contents**

- [Journals & Magazines](#)
- [Conference Proceedings](#)
- [Standards](#)

**Search**

- [By Author](#)
- [Basic](#)
- [Advanced](#)
- [CrossRef](#)

**Member Services**

- [Join IEEE](#)
- [Establish IEEE Web Account](#)
- [Access the IEEE Member Digital Library](#)

**IEEE Enterprise**

- [Access the IEEE Enterprise File Cabinet](#)

[Print Format](#)[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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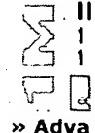
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[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

**Quick Links**

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

#### Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

#### Search

- By Author
- Basic
- Advanced
- CrossRef

#### Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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computer <phrase> internal  
<phrase> environment

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#### Search Options:

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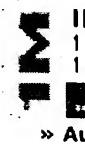
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List  Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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## Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

## Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

## Search

- By Author
- Basic
- Advanced
- CrossRef

## Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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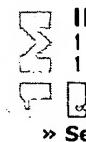
Example: Enter Lockett S to obtain a list of authors with the last name Lockett and first name initial S.  
 OR » Select a letter to browse the author list:

**A B C D E F G H I J K L M N O P Q R S T U V W X Y Z | ALL**

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<a href="#">Davis A.</a>	<a href="#">Davis A. A.</a>	<a href="#">Davis A. B.</a>	<a href="#">Davis A. E.</a>	<a href="#">Davis A</a>
<a href="#">Davis A. J.</a>	<a href="#">Davis A. K.</a>	<a href="#">Davis A. L.</a>	<a href="#">Davis A. M.</a>	<a href="#">Davis A</a>
<a href="#">Davis A. O.</a>	<a href="#">Davis A. P.</a>	<a href="#">Davis A. R.</a>	<a href="#">Davis A. S.</a>	<a href="#">Davis A</a>
<a href="#">Davis A. W.</a>	<a href="#">Davis B.</a>	<a href="#">Davis B. A.</a>	<a href="#">Davis B. C.</a>	<a href="#">Davis E</a>
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## Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

## Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

## Search

- By Author
- Basic
- Advanced
- CrossRef

## Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Demonstration of a fiber optic array of three-axis magnetometers for undersea application**

Bucholtz, F.; Dagenais, D.M.; Villarruel, C.A.; Kirkendall, C.K.; McVicker, J.A.; Davis, A.R.; Patrick, S.S.; Koo, K.P.; Wang, G.; Valo, H.; Eidem, E.J.; Andersen, A.; Lund, T.; Gjessing, R.; Knudsen, T.; Magnetics, IEEE Transactions on , Volume: 31 , Issue: 6 , Nov. 1995 Pages:3194 - 3196

[\[Abstract\]](#) [\[PDF Full-Text \(312KB\)\]](#) **IEEE JNL**
**2 Multichannel fiber-optic magnetometer system for undersea measurements**

Bucholtz, F.; Villarruel, C.A.; Davis, A.R.; Kirkendall, C.K.; Dagenais, D.M.; McVicker, J.A.; Patrick, S.S.; Koo, K.P.; Gunnar Wang; Valo, H.; Lund, T.; Andersen, A.G.; Gjessing, R.; Eidem, E.J.; Knudsen, T.; Lightwave Technology, Journal of , Volume: 13 , Issue: 7 , July 1995 Pages:1385 - 1395

[\[Abstract\]](#) [\[PDF Full-Text \(1132KB\)\]](#) **IEEE JNL**
**3 Gain-clamped SOA with 1-11 dB variable gain based on a three-cont tunable DBR laser**

Sosabowski, J.; Davies, A.R.; Penty, R.V.; White, I.H.; Lasers and Electro-Optics Europe, 2003. CLEO/Europe. 2003 Conference on , June 2003 Pages:162

[\[Abstract\]](#) [\[PDF Full-Text \(210KB\)\]](#) **IEEE CNF**
**4 64-element time-division multiplexed interferometric sensor array w EDFA telemetry**

Kersey, A.D.; Dandridge, A.; Davis, A.R.; Kirdendall, C.K.; Marrone, M.J.; Gro D.G.; Optical Fiber Communications, 1996. OFC '96 , 25 Feb.-1 March 1996 Pages:270 - 271

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[Abstract] [PDF Full-Text (208KB)] IEEE CNF

**5 1-to N-way phased array resonator with phase conjugate mirror**

*Jenkins, R.M.; Banerji, J.; Davies, A.R.;*

*Lasers and Electro-Optics Europe, 2000. Conference Digest. 2000 Conference on , 10-15 Sept 2000*

*Pages:1 pp.*

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[Abstract] [PDF Full-Text (104KB)] IEEE CNF

**6 Laser Resonators with Self-Imaging Waveguides**

*Banerji, J.; Davies, A.R.; Jenkins, R.M.;*

*Lasers and Electro-optics Europe, 1996. CLEO/Europe., Conference on , 8-13 : 1996*

*Pages:168 - 168*

---

[Abstract] [PDF Full-Text (84KB)] IEEE CNF

**7 Low wavelength drift uncooled laser using tuned distributed Bragg reflectors**

*Davies, A.R.; Fan, S.; Williams, K.A.; Penty, R.V.; White, I.H.;*

*Lasers and Electro-Optics Society, 2002. LEOS 2002. The 15th Annual Meeting of the IEEE ,Volume: 2 , 10-14 Nov. 2002*

*Pages:861 - 862 vol.2*

---

[Abstract] [PDF Full-Text (222KB)] IEEE CNF

**8 Variable gain operation of a gain-clamped sampled grating laser amplifier**

*Davies, A.R.; Williams, K.A.; Penty, R.V.; White, I.H.; Glick, M.; McAuley, D.;*

*Lasers and Electro-Optics, 2002. CLEO '02. Technical Digest. Summaries of Papers Presented at the , 19-24 May 2002*

*Pages:372 - 373 vol.1*

---

[Abstract] [PDF Full-Text (346KB)] IEEE CNF

**9 Remote Fiber Optic AC Magnetometer**

*Davis, A.R.; Patrick, S.S.; Dandridge, A.; Bucholtz, F.;*

*Optical Fiber Sensors Conference, 1992. 8th , Jan. 29-31, 1992*

*Pages:414 - 417*

---

[Abstract] [PDF Full-Text (184KB)] IEEE CNF

**10 Video compression employing algorithm using temporal blocking structures**

*Gregory, N.; Davies, A.R.; Darnell, M.; Boussakta, S.;*

*Electronics Letters ,Volume: 37 , Issue: 9 , 26 April 2001*

*Pages:563 - 564*

---

[Abstract] [PDF Full-Text (272KB)] IEE JNL

**11 Undersea performance of eight-element fibre optic magnetometer :**

*Bucholtz, F.; Wang, G.; Kirkendall, C.K.; Villaruel, C.A.; Davis, A.R.; Dagenais*

D.M.; McVicker, J.A.; Patrick, S.S.; Koo, K.P.; Andersen, A.; Valo, H.; Gjessing, E.;  
Eidem, E.J.; Knudsen, T.;  
Electronics Letters ,Volume: 30 , Issue: 23 , 10 Nov. 1994  
Pages:1974 - 1975

[\[Abstract\]](#) [\[PDF Full-Text \(184KB\)\]](#) [IEE JNL](#)

---

**12 Fibre optic magnetometer system for undersea applications**

Bucholtz, F.; Villaruel, C.A.; Kirkendall, C.K.; Dagenais, D.M.; McVicker, J.A.;  
Davis, A.R.; Patrick, S.S.; Koo, K.P.; Wathen, K.G.; Dandridge, A.; Wang, G.;  
Lund, T.; Valo, H.;  
Electronics Letters ,Volume: 29 , Issue: 11 , 27 May 1993  
Pages:1032 - 1033

[\[Abstract\]](#) [\[PDF Full-Text \(164KB\)\]](#) [IEE JNL](#)

---

**13 Remote fibre-optic AC magnetometer**

Davis, A.R.; Patrick, S.S.; Dandridge, A.; Bucholtz, F.;  
Electronics Letters ,Volume: 28 , Issue: 3 , 30 Jan. 1992  
Pages:271 - 273

[\[Abstract\]](#) [\[PDF Full-Text \(256KB\)\]](#) [IEE JNL](#)

---

**14 Curve and corner extraction using the multiresolution Fourier trans**

Davies, A.R.; Wilson, R.;  
Image Processing and its Applications, 1992., International Conference on , 7-  
Apr 1992  
Pages:282 - 285

[\[Abstract\]](#) [\[PDF Full-Text \(244KB\)\]](#) [IEE CNF](#)

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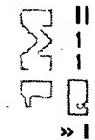
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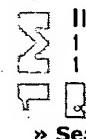
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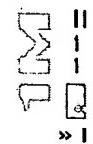
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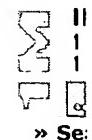
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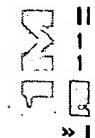
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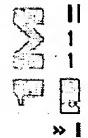
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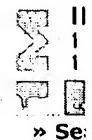
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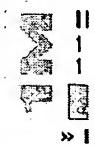
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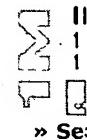


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